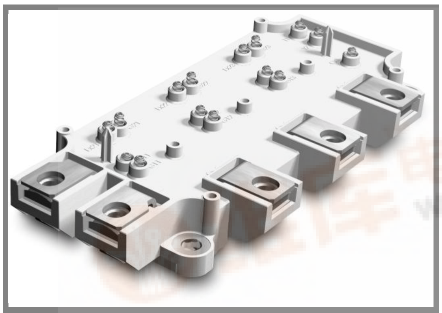
SEMiX 101GD128Ds



SEMIX®13s

SPT IGBT Modules

SEMiX 101GD128Ds

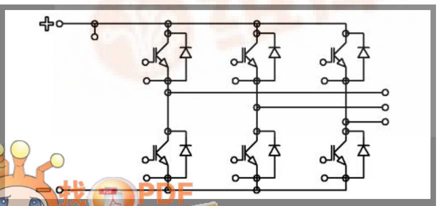
Target Data

Features

- Homogeneous Si
- SPT = Soft-Punch-Through technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability

Typical Applications

- AC inverter drives
- UPS
- Electronic welders f_{sw} up to 20 kHz



Absolute Maximum Ratings T_{case} = 25°C, unless otherwise specified

Symbol	Conditions	Values	Units
IGBT			
V_{CES}		1200	V
I_C	T_c = 25 (80) °C	100 (70)	A
I_{CRM}	t_p = 1 ms	100	A
V_{GES}		± 20	V
T_{vj}, (T_{stg})	$T_{OPERATION} \leq T_{stg}$	- 40 ... + 150 (125)	°C
V_{isol}	AC, 1 min.	4000	V
Inverse diode			
I_F	T_c = 25 (80) °C	80 (50)	A
I_{FRM}	t_p = 1 ms	100	A
I_{FSM}	t_p = 10 ms; sin.; T_j = 25 °C	550	A

Characteristics T_{case} = 25°C, unless otherwise specified

Symbol	Conditions	min.	typ.	max.	Units
IGBT					
$V_{GE(th)}$	$V_{GE} = V_{CE}$, I_C = 2 mA	4,5	5	6,5	V
I_{CES}	V_{GE} = 0, $V_{CE} = V_{CES}$, T_j = 25 (125) °C			0,3	mA
$V_{CE(TO)}$	T_j = 25 (125) °C		1 (0,9)	1,15 (1,05)	V
r_{CE}	V_{GE} = 15 V, T_j = 25 (125) °C		18 (24)	24 (30)	mΩ
$V_{CE(sat)}$	I_{Cnom} = 50 A, V_{GE} = 15 V, T_j = 25 (125) °C, chip level		1,9 (2,1)	2,35 (2,55)	V
C_{ies}	under following conditions		4,5		nF
C_{oes}	V_{GE} = 0, V_{CE} = 25 V, f = 1 MHz		0,6		nF
C_{res}			0,55		nF
L_{CE}			20		nH
$R_{CC'+EE'}$	terminal-chip, T_c= 25 (125) °C		0,7 (1)		mΩ
$t_{d(on)}/t_r$	V_{CC} = 600 V, I_{Cnom} = 50 A		115 / 30		ns
$t_{d(off)}/t_f$	V_{GE} = ± 15 V		340 / 50		ns
E_{on} (E_{off})	$R_{Gon} = R_{Goff}$ = 8 Ω, T_j = 125 °C		5,1 (5,2)		mJ
Inverse diode					
$V_F = V_{EC}$	I_{Fnom} = 50 A; V_{GE} = 0 V; T_j = 25 (125) °C, chip level		2 (1,8)	2,5 (2,3)	V
$V_{(TO)}$	T_j = 25 (125) °C		1,1	1,2	V
r_T	T_j = 25 (125) °C		18	26	mΩ
I_{RRM}	I_{Fnom} = 50 A; T_j = 25 (125) °C		77		A
Q_{rr}	di/dt = 2840 A/µs		7,8		µC
E_{rr}	V_{GE} = -15 V		2,9		mJ
Thermal characteristics					
$R_{th(j-c)}$	per IGBT			0,27	K/W
$R_{th(j-c)D}$	per Inverse Diode			0,62	K/W
$R_{th(j-c)FD}$	per FWD				K/W
$R_{th(c-s)}$	per module		0,04		K/W
Temperature sensor					
R_{25}	T_c = 25 °C		5 ±5%		kΩ
$B_{25/85}$	$R_2=R_1\exp[B(1/T_2-1/T_1)]$; T[K];B		3420		K
Mechanical data					
M_s/M_t	to heatsink (M5) / for terminals (M6)	3/2,5		5 /5	Nm
w			290		g

SEMiX 101GD128Ds

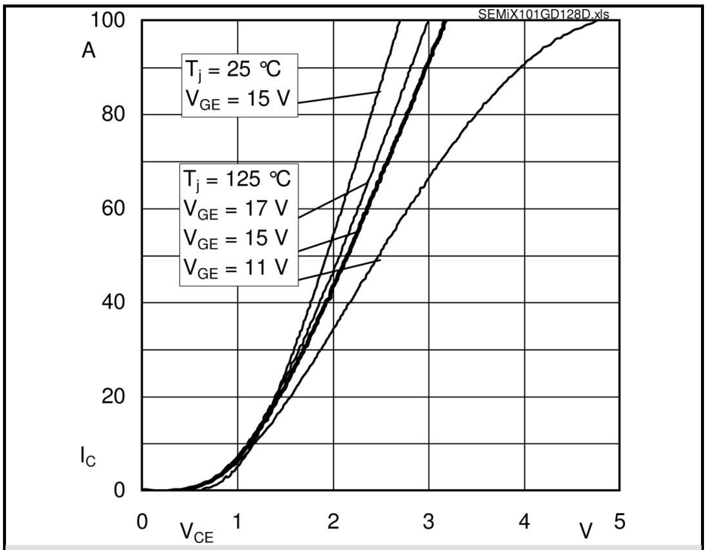


Fig. 1 Typ. output characteristic, inclusive $R_{CC'+ EE'}$

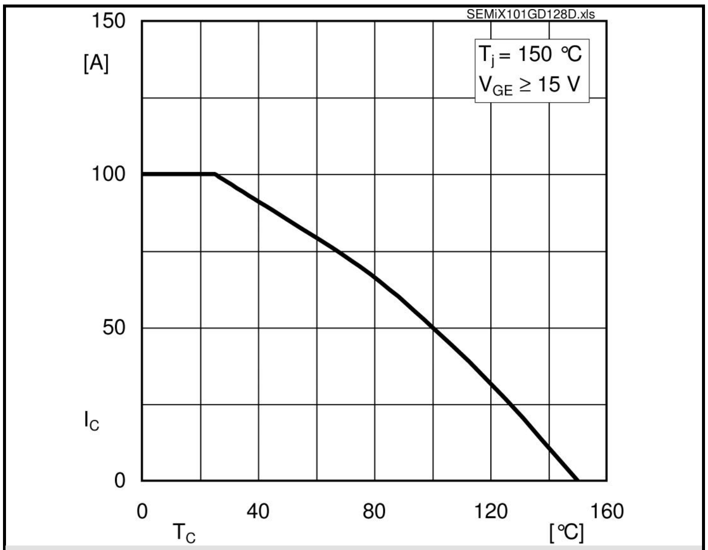


Fig. 2 Rated current vs. temperature $I_C = f (T_C)$

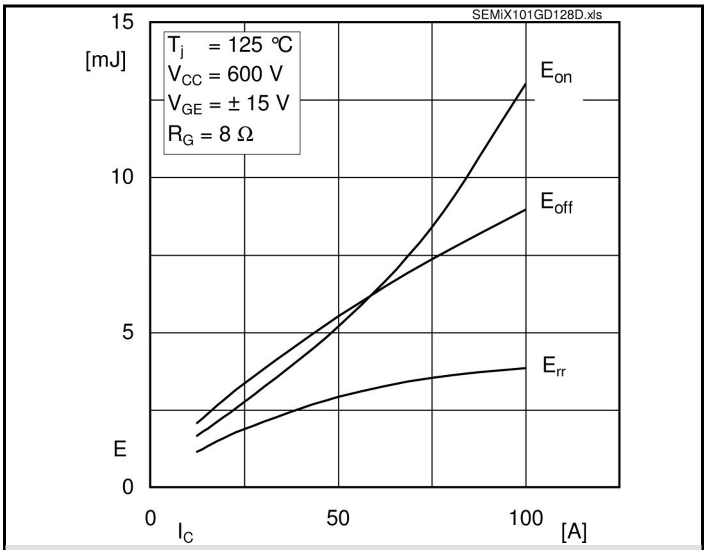


Fig. 3 Typ. turn-on /-off energy = f (I_C)

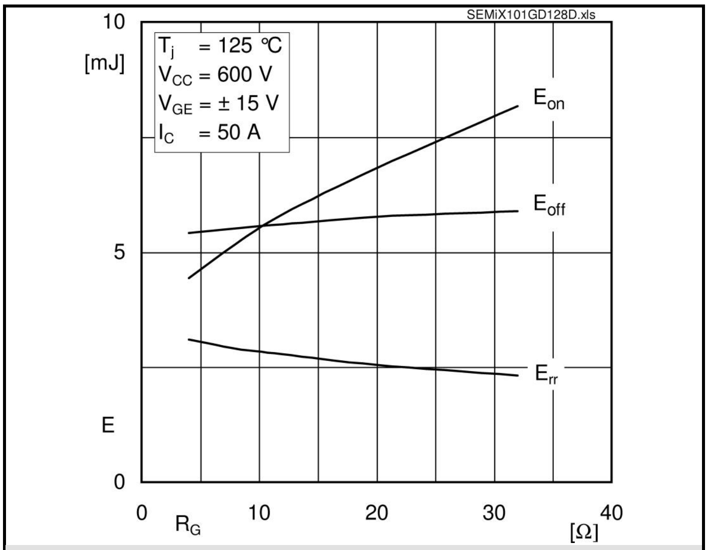


Fig. 4 Typ. turn-on /-off energy = f (R_G)

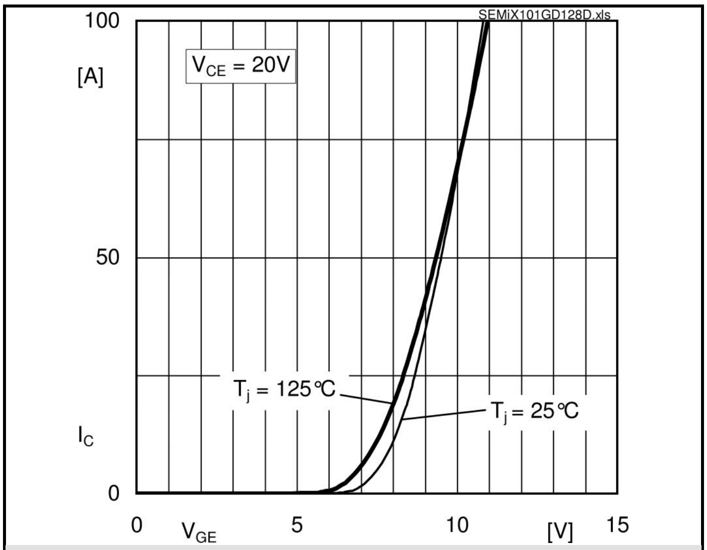


Fig. 5 Typ. transfer characteristic

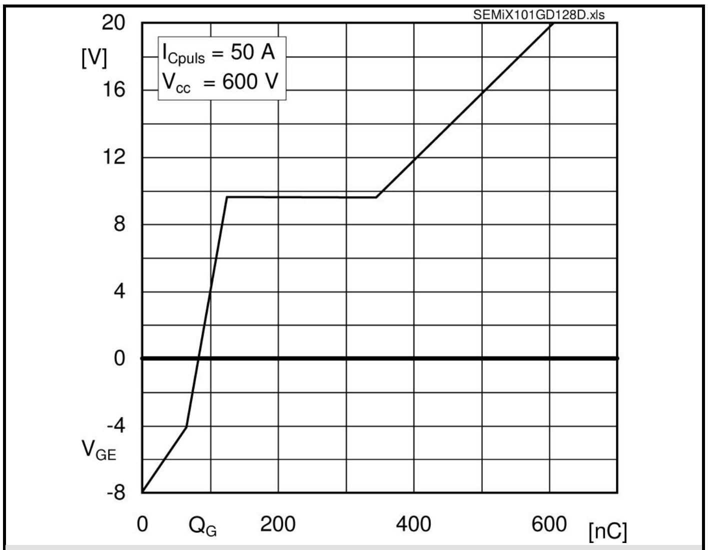


Fig. 6 Typ. gate charge characteristic

SEMiX 101GD128Ds

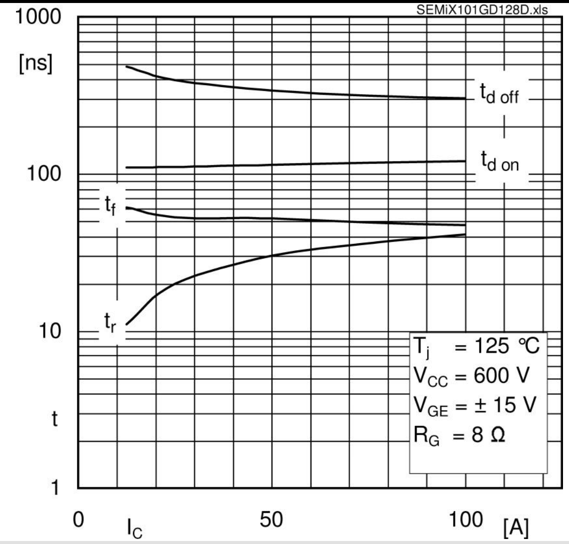


Fig. 7 Typ. switching times vs. I_C

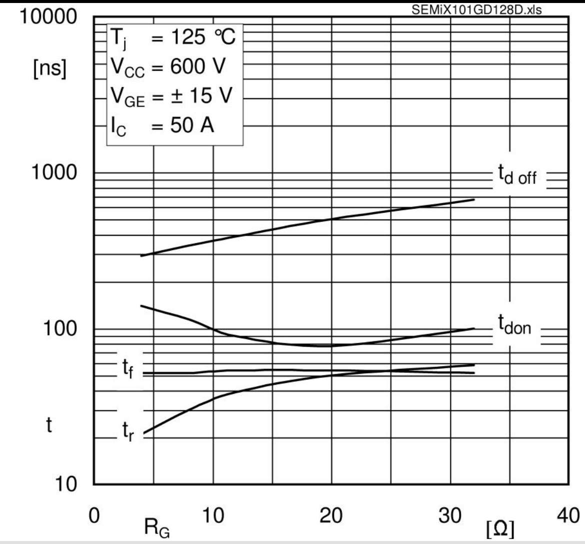


Fig. 8 Typ. switching times vs. gate resistor R_G

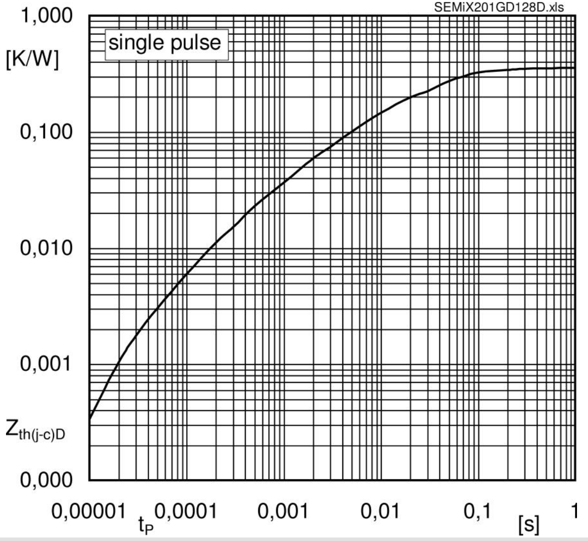


Fig. 9 Transient thermal impedance of IGBT

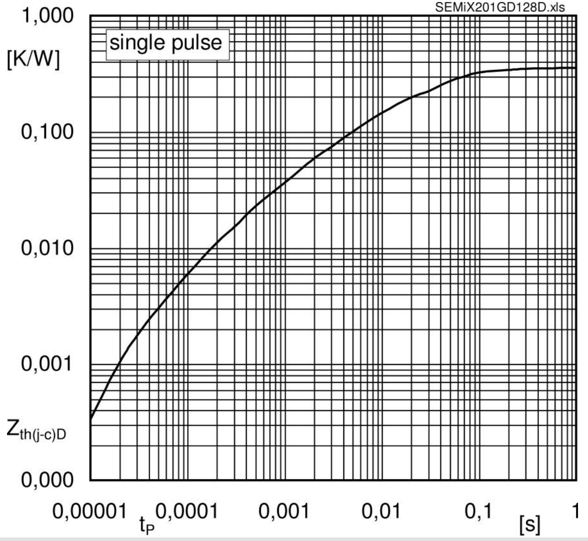


Fig. 10 Transient thermal impedance of FWD

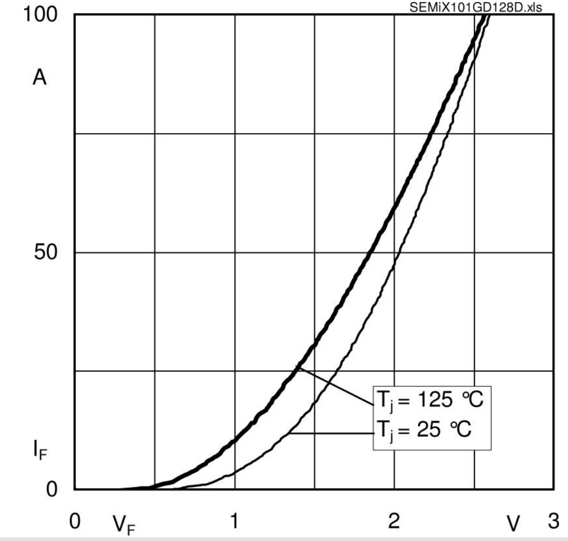


Fig. 11 CAL diode forward characteristic

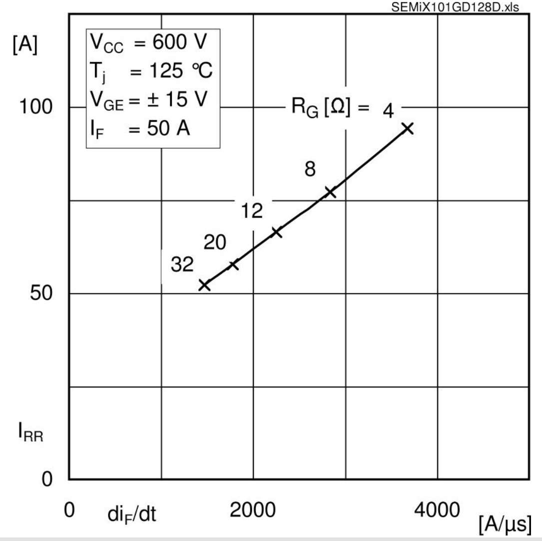


Fig. 12 Typ. CAL diode peak reverse recovery current

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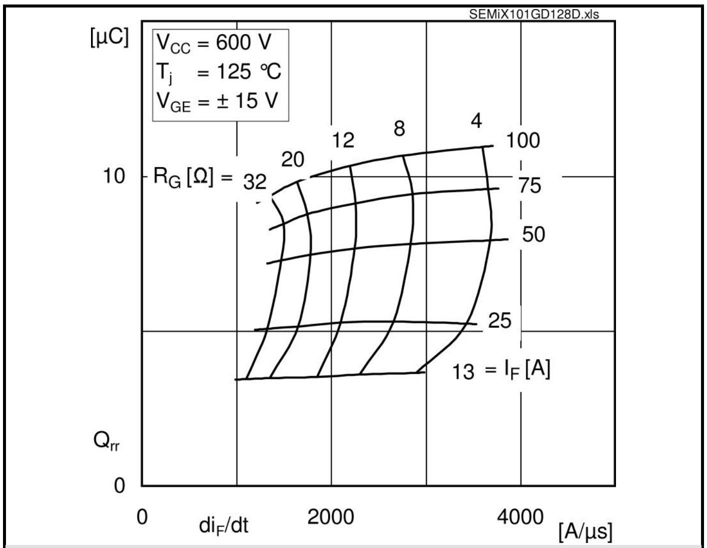
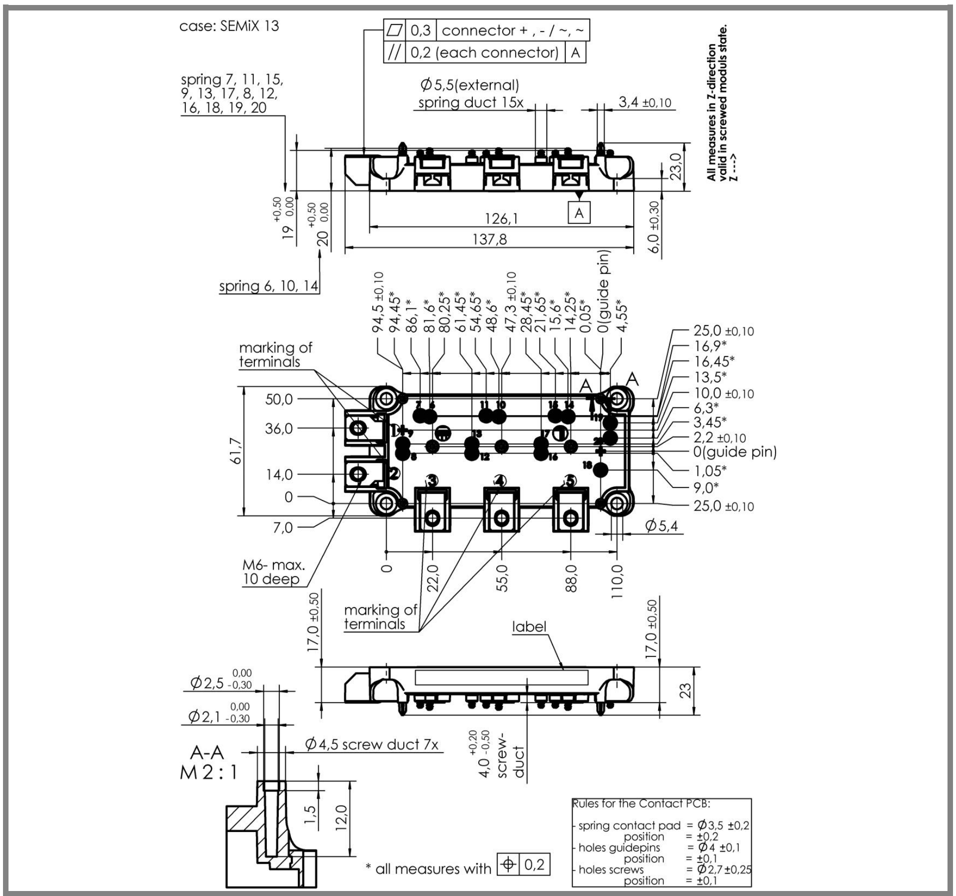
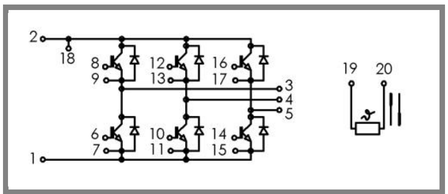


Fig. 13 Typ. CAL diode recovered charge



Case SEMiX 13s



GD pinout SEMiX 13s

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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